Product Description

TOP VISUAL High Resolution Contact Silicon AFM Cantilevers VIT_P_C series are specially designed for tip or laser spot precise positioning over the point of interest.

Typical Resonant Frequency 16 kHz (guaranteed range 8-25 kHz), Typical Force Constant 0.3 N/m (guaranteed range 0.06-1N/m).

Cantilevers don't have any reflective coating.

Probes are packed in boxes with 15 pieces.

General Features

Material	Single Crystal Silicon, N-type, 0.01-0.025 Ohm-cm, Antimony doped
Chip size	3.4x1.6x0.3mm
Reflective side coating	No coating
Tip coating	No
Tip curvature radius	typical 6nm, guaranteed 10nm

Special Features

Cantilever series	Cantilever length, L±10µm	Cantilever width, W±5µm	Cantilever thickness, T±1.0µm	Resonant frequency, kHz			Force constant, N/m		
				min	typical	max	min	typical	max
VIT_P_C	450	50	2.0	7	15	25	0.02	0.2	0.75